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(12) **United States Design Patent**
Teranishi et al.

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- (54) **PROBE PIN**
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(**) Term: **15 Years**

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(51) **LOC (10) CL.** **10-04**

(52) **U.S. CL.**
USPC **D10/78**

(58) **Field of Classification Search**
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G01R 1/06727; G01R 1/06733; G01R
1/06738; G01R 1/06744; G01R 1/0675;
G01R 1/06766; G01R 1/06772; G01R
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See application file for complete search history.

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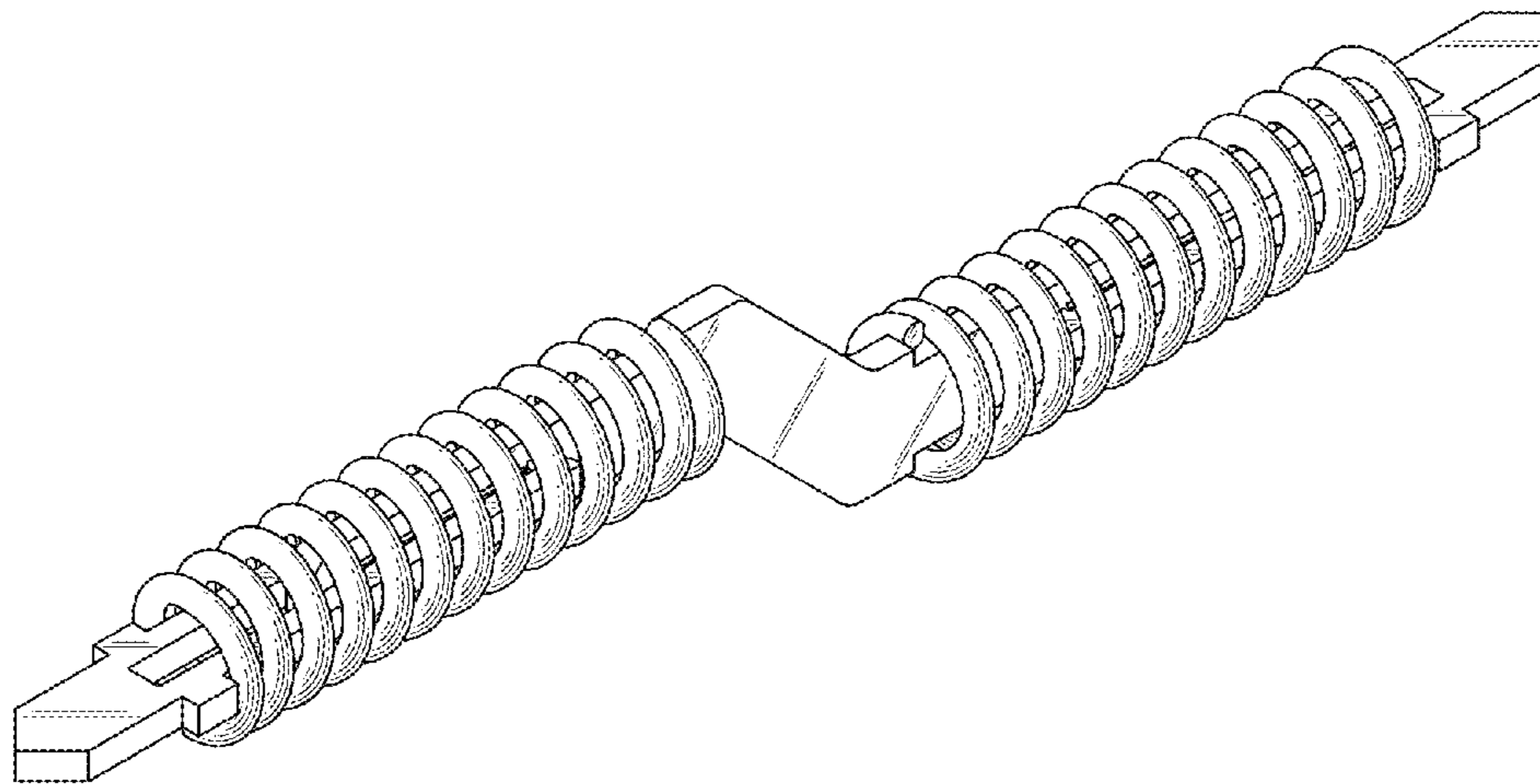
(57) **CLAIM**

The ornamental design for a probe pin, as shown and described.

DESCRIPTION

FIG. 1 is a top front perspective view of a probe pin showing our new design;
FIG. 2 is a front view thereof;
FIG. 3 is a rear view thereof;
FIG. 4 is a left side view thereof;
FIG. 5 is a right side view thereof;
FIG. 6 is a top view thereof; and,
FIG. 7 is a bottom view thereof.
The shade lines in the figures show contour and not surface ornamentation.

1 Claim, 4 Drawing Sheets



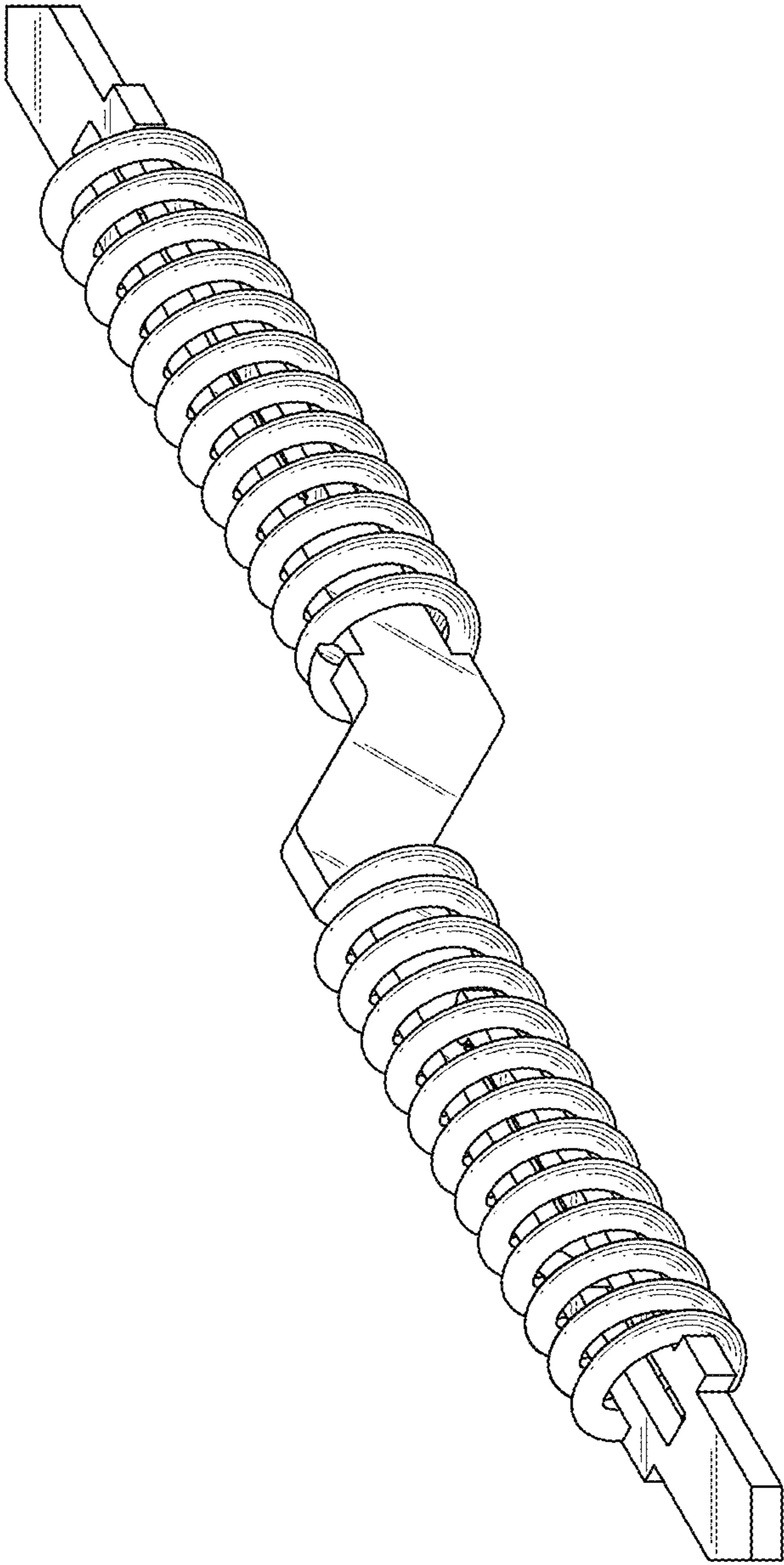


FIG. 1

FIG. 2

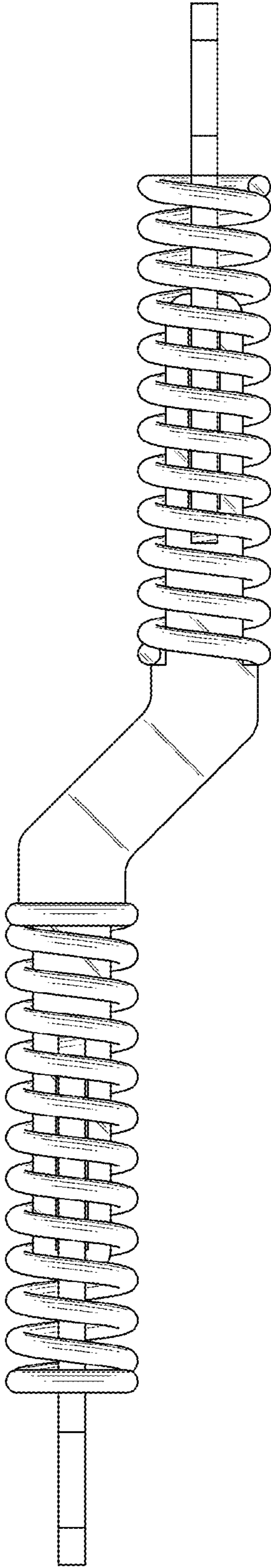
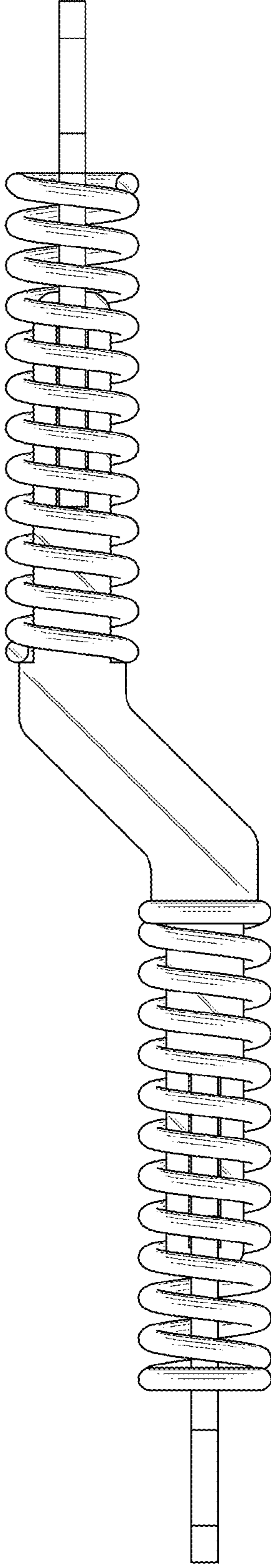


FIG. 3



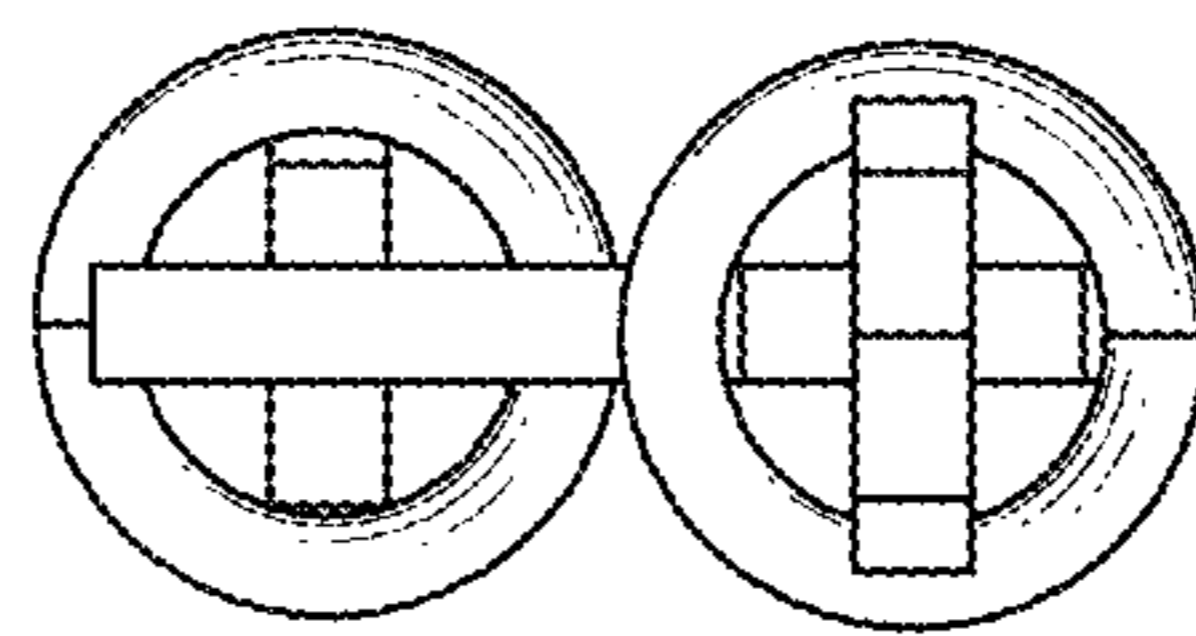


FIG. 5

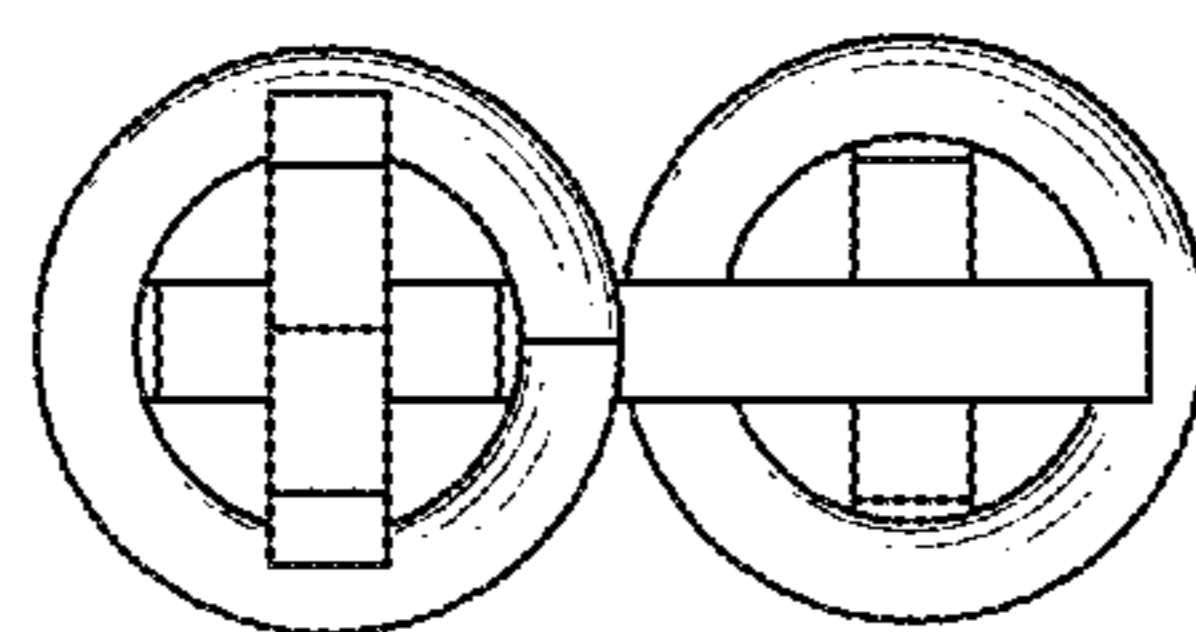


FIG. 4

FIG. 6

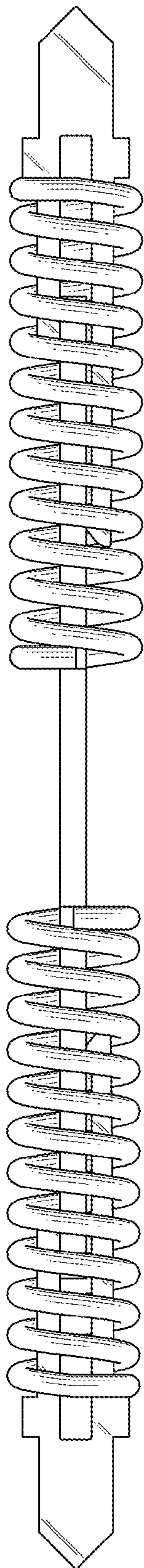


FIG. 7

